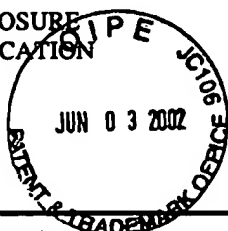


FORM PTO-1449 INFORMATION DISCLOSURE CITATION IN AN APPLICATION	DOCKET NUMBER SLA1038	APPLICATION NUMBER 09/683,667
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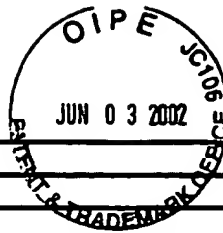
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